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United States Patent [19]

[11] **Patent Number: Des. 425,919**

Burkhart et al.

[45] **Date of Patent: ** *May 30, 2000**

[54] **ELECTROSTATIC CHUCK WITH IMPROVED SPACING MASK AND WORKPIECE DETECTION DEVICE**

5,745,332 4/1998 Burkhart et al. 361/234

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[57] **CLAIM**

[73] Assignee: **Applied Materials, Inc.**, Santa Clara, Calif.

The ornamental design for an electrostatic chuck with improved spacing mask and workpiece detection device, as shown.

[*] Notice: This patent is subject to a terminal disclaimer.

DESCRIPTION

[**] Term: **14 Years**

FIG. 1 depicts a top view of the electrostatic chuck with improved spacing mask and workpiece detection device; FIG. 2 depicts an elevation view of the electrostatic chuck when looking up along the y-axis of FIG. 1; FIG. 3 depicts a detailed view of part of a surface and circumferential edge of the electrostatic chuck seen of FIG. 2; FIG. 4 depicts an elevation view of the electrostatic chuck when looking down along the y-axis of FIG. 1; FIG. 5 depicts an elevation view of the electrostatic chuck when looking to the left along the x-axis of FIG. 1, the view when looking to the right being a mirror image to that of FIG. 5; and, FIG. 6 is a bottom view of the electrostatic chuck.

[21] Appl. No.: **29/079,585**

[22] Filed: **Nov. 14, 1997**

[51] **LOC (7) Cl.** **15-09**

[52] **U.S. Cl.** **D15/140**

[58] **Field of Search** D15/140; 118/728; 279/128; 361/230-233, 234, 235

[56] **References Cited**

U.S. PATENT DOCUMENTS

5,671,116 9/1997 Husain 361/234
5,691,876 11/1997 Chen et al. 361/234

1 Claim, 2 Drawing Sheets

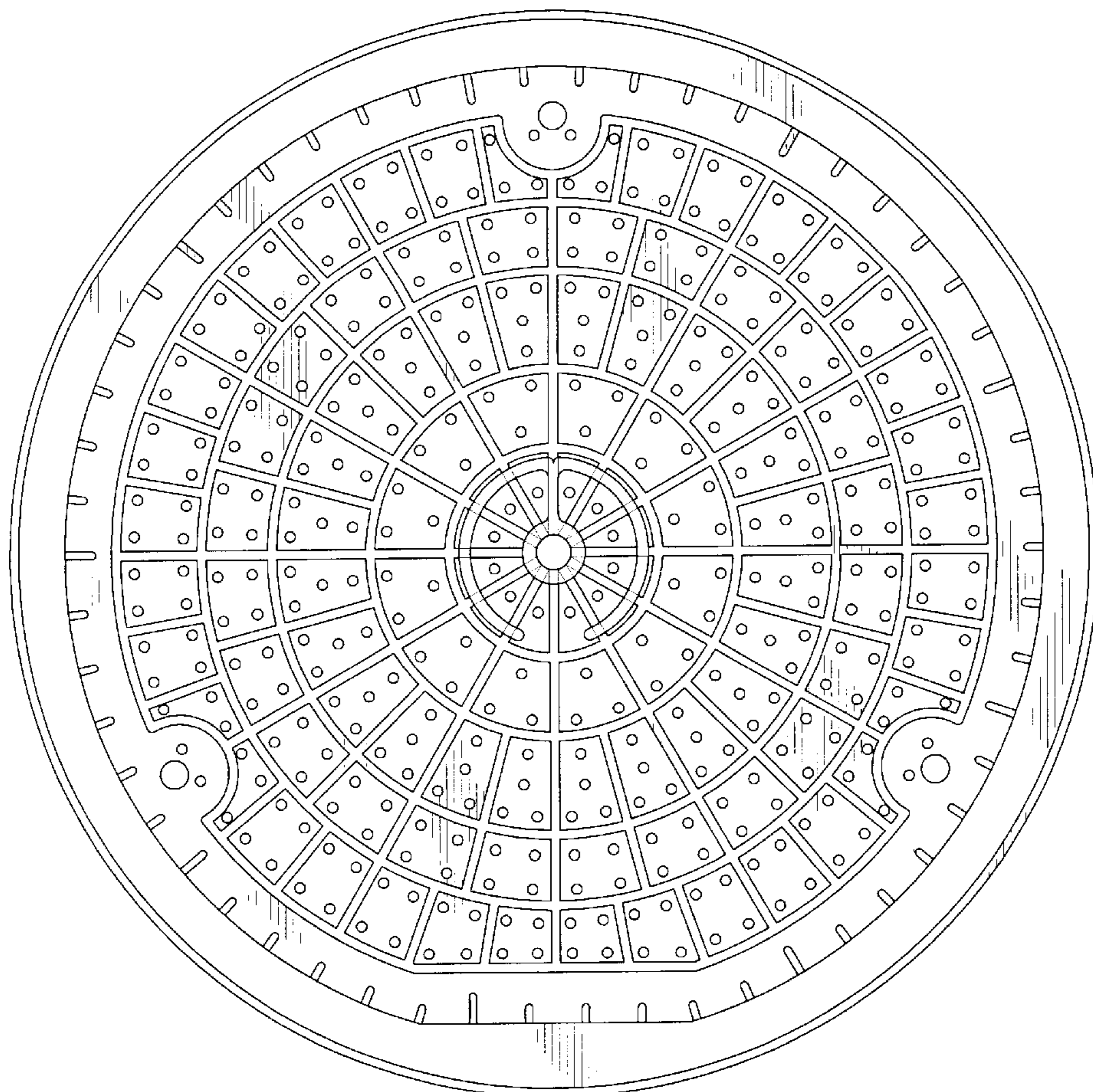


FIG. 1

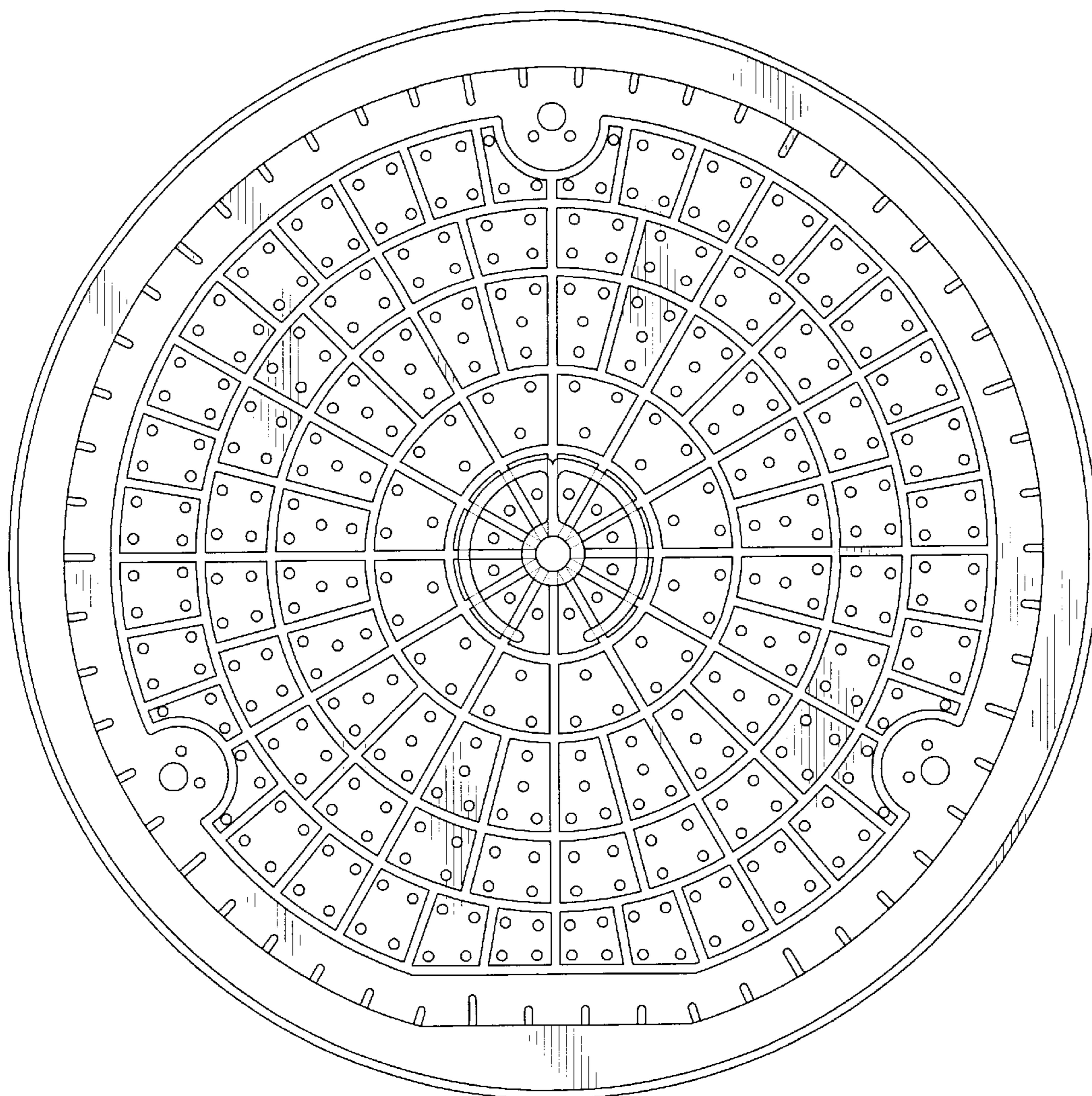


FIG. 2

FIG. 3

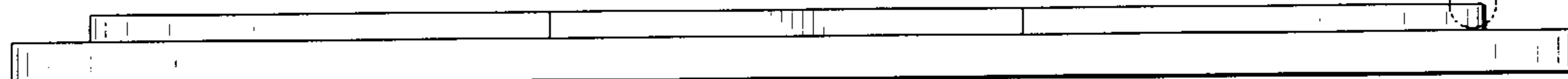


FIG. 3

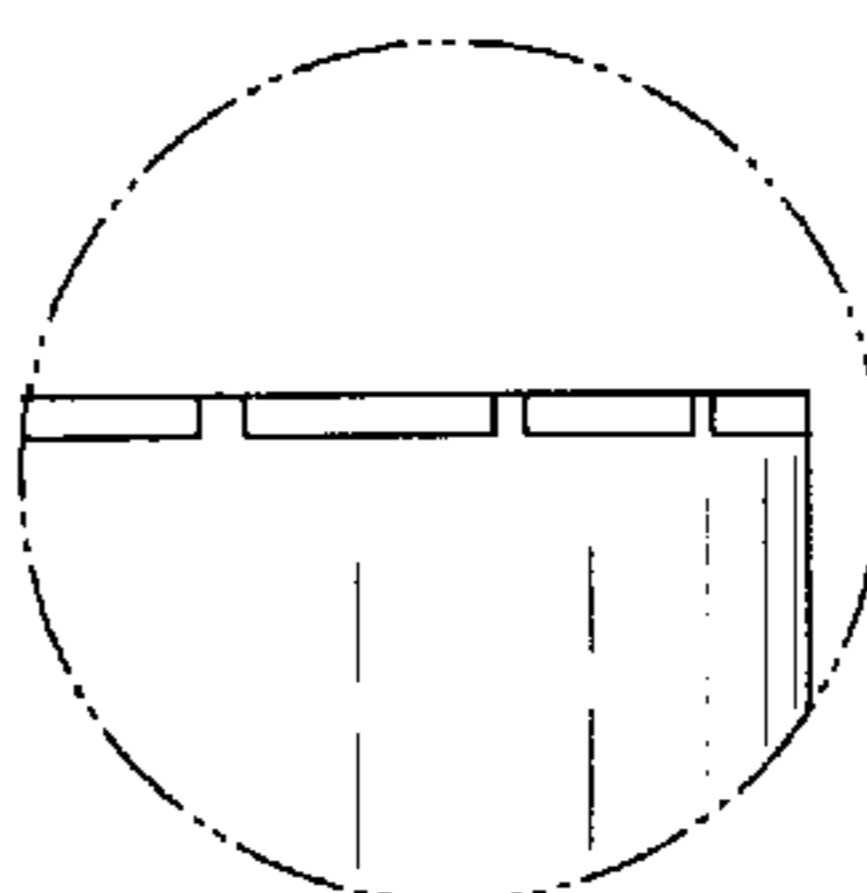


FIG. 4

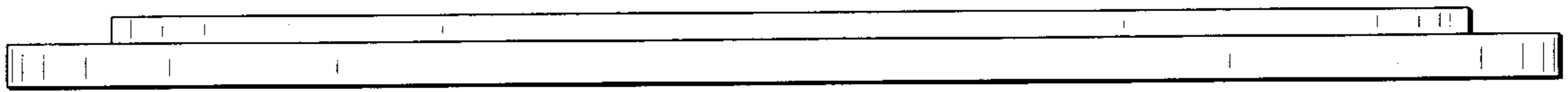


FIG. 5

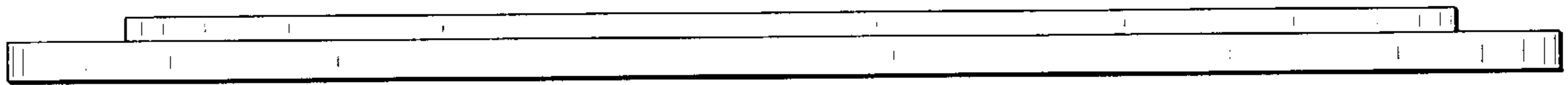


FIG. 6

